

Docket No.: XENOCS 3.3-001

(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Andrew T. Zidel

In re Patent Application of:

Hoghoj et al.

Application No.: 10/506,716

Group Art Unit: 2882

Filed: September 7, 2004

Examiner: J. Corbett

For: OPTICAL UNIT AND ASSOCIATED

METHOD

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

SUBMISSION OF INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR § 1.97(B)

Dear Sir:

It is respectfully requested that the accompanying Information Disclosure Statement, filed after issuance of a Notice of Allowance, be considered pursuant to 37 C.F.R. § 1.97(b). References CD and CE were cited in a Search Report issued in connection with applicant's corresponding French Application. The U.S. Patent cited in the Search Report, No. 6,278,764, was previously cited in the instant application. A copy of each non-US patent or patent application, and the search report, are enclosed. In the event that any additional fee is due in connection with the present petition, the same should be charged to our Deposit Account No. 12-1095.

Dated: January 29, 2007

Respectfully submitted,

Andrew T. Zidel

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PTO/SB/08A/B (09-06) Approved for use through 03/31/2007. OMB 0651-0031
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Substitute for form 1449/PTO				Complete if Known	
INFORMATION DISCLOSURE				Application Number	10/506,716-Conf. #4876
				Filing Date	September 7, 2004
STATEMENT BY APPLICANT (Use as many sheets as necessary)			PPLICANT	First Named Inventor	Peter Hoghoj
				Art Unit	2882
			necessary)	Examiner Name	J. Corbett
Sheet	1	of	1	Attorney Docket Number	XENOCS 3.3-001

			U.S. PA	TENT DOCUMENTS		
Examiner Initials*	Cite No.1	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant	
		Number-Kind Code ² (if known)			Figures Appear	
	AA*	US-6,226,349	05-01-2001	Schuster et al.		

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No.1	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
	ВА	WO-108162	02-01-2001	Univ California		+	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. * CITE NO.: Those application(s) which are marked with an single asterisk (*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS						
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²			
	CA	G.E. ICE, "Microbeam Forming Methods for Synchrotron Radiation,"© 1997				
	СВ	OVONYX; Design News; "Focusing ring: first step toward scanning X-ray microsope," 13 pages				
	СС	Research & Development, November 1988 by B. Volbert "New X-ray Spectrometer Technology Improves Both Speed and Accuracy," 8 pages				
	CD	MORAWE CH ET AL., entitled "Production of x-ray multilayer coatings by plasma sputtering" (VIDE; VIDE: SCIENCE, TECHNIQUE ET APPLICATIONS 1999 SOC FRANCAISE DU VIDE, FRANCE, vol. 4 (4), no. 294, 1999, pages 467-472)				
	CE	PING LEE, entitled: "Uniform and graded multilayers as X-ray optical elements" (APPLIED OPTICS USA, vol. 22, no. 8, 15 April 1983 (1983-04-15), pages 1241-1246)				

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Examiner	Date
Signature	Considered

¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached. + counterpart of U.S. Patent No. 6,278,764